# **MOSFET** – POWERTRENCH®, N-Channel Shielded Gate

# **80 V, 123 A, 4.3 m** $\Omega$

### **Description**

This N-Channel MV MOSFET is produced using ON Semiconductor's advanced POWERTRENCH® process that incorporates Shielded Gate technology. This process has been optimized to minimise on-state resistance and yet maintain superior switching performance with best in class soft body diode.

#### **Features**

- Shielded Gate MOSFET Technology
- Max  $r_{DS(on)} = 4.3 \text{ m}\Omega$  at  $V_{GS} = 10 \text{ V}$ ,  $I_D = 44 \text{ A}$
- Max  $r_{DS(on)} = 10.4 \text{ m}\Omega$  at  $V_{GS} = 6 \text{ V}$ ,  $I_D = 22 \text{ A}$
- 50% Lower Qrr than Other MOSFET Suppliers
- Lowers Switching Noise/EMI
- MSL1 Robust Package Design
- 100% UIL Tested
- RoHS Compliant

#### **Typical Applications**

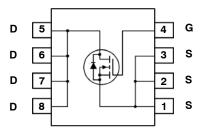
- Primary DC-DC MOSFET
- Synchronous Rectifier in DC-DC and AC-DC
- Motor Drive
- Solar



# ON Semiconductor®

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#### **ELECTRICAL CONNECTION**



**N-Channel MOSFET** 



Power 56 (PQFN8 5x6) CASE 483AE

#### **MARKING DIAGRAM**

\$Y&Z&3&K FDMS 4D4N08C

\$Y = ON Semiconductor Logo &Z = Assembly Plant Code &3 = Numeric Date Code

&K = Lot Code

FDMS4D4N08C = Specific Device Code

#### ORDERING INFORMATION

See detailed ordering and shipping information on page 2 of this data sheet.

# MOSFET MAXIMUM RATINGS (T<sub>A</sub> = 25°C, Unless otherwise specified)

Symbol		Para	meter		Ratings	Unit
$V_{DS}$	Drain to Source	Voltage			80	V
$V_{GS}$	Gate to Source \	/oltage			±20	V
I <sub>D</sub>	Drain Current	-Continuous	T <sub>C</sub> = 25°C	(Note 5)	123	Α
		-Continuous	T <sub>C</sub> = 100°C	(Note 5)	78	
		-Continuous	T <sub>A</sub> = 25°C	(Note 1a)	17	
		-Pulsed		(Note 4)	498	
E <sub>AS</sub>	Single Pulse Ava	alanche Energy		(Note 3)	486	mJ
$P_{D}$	Power Dissipation	n	T <sub>C</sub> = 25°C		125	W
	Power Dissipation	n	T <sub>A</sub> = 25°C	(Note 1a)	2.5	
T <sub>J</sub> , T <sub>STG</sub>	Operating and S	torage Junction Tempe	rature Range		-55 to +150	°C

Stresses exceeding those listed in the Maximum Ratings table may damage the device. If any of these limits are exceeded, device functionality should not be assumed, damage may occur and reliability may be affected.

# THERMAL CHARACTERISTICS

Symbol	Parameter	Ratings	Unit
$R_{ heta JC}$	Thermal Resistance, Junction to Case	1.0	°C/W
$R_{ heta JA}$	Thermal Resistance, Junction to Ambient (Note 1a)	50	

#### PACKAGE MARKING AND ORDERING INFORMATION

Device Marking	Device	Package	Shipping <sup>†</sup>
FDMS4D4N08C	FDMS4D4N08C	PQFN8 5×6 (Pb–Free/Halogen Free)	3000 Units/ Tape & Reel

<sup>†</sup>For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

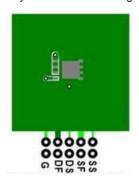
# **ELECTRICAL CHARACTERISTICS** (T<sub>J</sub> = 25°C unless otherwise noted)

Symbol	Parameter	Test Cond	itions	Min.	Тур.	Max.	Units
OFF CHARAC	TERISTICS		•		•		•
BV <sub>DSS</sub>	Drain to Source Breakdown Voltage	I <sub>D</sub> = 250 μA, V <sub>GS</sub> =	= 0 V	80			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, referenced to 25°C			63		mV/°C
I <sub>DSS</sub>	Zero Gate Voltage Drain Current	V <sub>DS</sub> = 64 V, V <sub>GS</sub> =	0 V			1	μΑ
I <sub>GSS</sub>	Gate to Source Leakage Current	V <sub>GS</sub> = ±20 V, V <sub>DS</sub> =	= 0 V			±100	nA
ON CHARACT	ERISTICS (Note NO TAG)				1		
V <sub>GS(th)</sub>	Gate to Source Threshold Voltage	V <sub>GS</sub> = V <sub>DS</sub> , I <sub>D</sub> = 25	0 μΑ	2.0	3.0	4.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	I <sub>D</sub> = 250 μA, refere	I <sub>D</sub> = 250 μA, referenced to 25°C		-8.2		mV/°C
r <sub>DS(on)</sub>	Static Drain to Source On	V <sub>GS</sub> = 10 V, I <sub>D</sub> = 44 A			3.7	4.3	mΩ
	Resistance	V <sub>GS</sub> = 6 V, I <sub>D</sub> = 22 A	V <sub>GS</sub> = 6 V, I <sub>D</sub> = 22 A		5.7	10.4	
		V <sub>GS</sub> = 10 V, I <sub>D</sub> = 44 A, T <sub>J</sub> = 125°C			5.9	7.2	
9FS	Forward Transconductance	V <sub>DS</sub> = 5 V, I <sub>D</sub> = 44 A			98		S
DYNAMIC CHA	ARACTERISTICS						
C <sub>ISS</sub>	Input Capacitance	V <sub>DS</sub> = 40 V, V <sub>GS</sub> =		2920	4090	pF	
C <sub>OSS</sub>	Output Capacitance	f = 1 MHz			1045	1465	
C <sub>RSS</sub>	Reverse Transfer Capacitance				35	50	
R <sub>G</sub>	Gate Resistance			0.1	1.3	2.5	Ω
SWITCHING C	HARACTERISTICS						
t <sub>d(on)</sub>	Turn – On Delay Time		$V_{DD}$ = 40 V, $I_{D}$ = 44 A, $V_{GS}$ = 10 V, $R_{GEN}$ = 6 $\Omega$		17	31	ns
t <sub>r</sub>	Rise Time	$V_{GS} = 10 \text{ V, } H_{GEN} = 10 \text{ V}$			7	15	
t <sub>d(off)</sub>	Turn – Off Delay Time	1			25	40	
t <sub>f</sub>	Fall Time	1			5	10	7
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 10 V			40	56	nC
Qg	Total Gate Charge	V <sub>GS</sub> = 0 V to 6 V	V <sub>DD</sub> = 40 V,		25	35	
Q <sub>gs</sub>	Gate to Source Charge		' I <sub>D</sub> = 44 A		13		
Q <sub>gd</sub>	Gate to Drain "Miller" Charge	1			8		
Q <sub>oss</sub>	Output Charge	V <sub>DD</sub> = 40 V, V <sub>GS</sub> =	0 V		60		nC
Q <sub>sync</sub>	Output Charge	rge V <sub>DS</sub> = 0 V, I <sub>D</sub> = 44 A			35		
DRAIN-SOUR	CE DIODE CHARACTERISTICS						
V <sub>SD</sub>	Source to Drain Diode Forward	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 2.1 A (Note 2)			0.7	1.2	V
	Voltage	V <sub>GS</sub> = 0 V, I <sub>S</sub> = 44 A (Note 2)			0.8	1.3	
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 22 A, di/dt = 30	I <sub>F</sub> = 22 A, di/dt = 300 A/μs		26	42	ns
Q <sub>rr</sub>	Reverse Recovery Charge	1	Ī		44	71	nC
t <sub>rr</sub>	Reverse Recovery Time	I <sub>F</sub> = 22 A, di/dt = 10	000 A/μs		20	32	ns
Q <sub>rr</sub>	Reverse Recovery Charge				106	169	nC

Product parametric performance is indicated in the Electrical Characteristics for the listed test conditions, unless otherwise noted. Product performance may not be indicated by the Electrical Characteristics if operated under different conditions.

#### NOTES:

1.  $R_{\theta JA}$  is determined with the device mounted on a 1 in<sup>2</sup> pad 2 oz copper pad on a 1.5  $\times$  1.5 in. board of FR-4 material.  $R_{\theta CA}$  is determined by the user's board design.



a) 50°C/W when mounted on a 1 in<sup>2</sup> pad of 2 oz copper.



b) 125°C/W when mounted on a minimum pad of 2 oz copper.

- Pulse Test: Pulse Width < 300 μs, Duty cycle < 2.0%.</li>
  E<sub>AS</sub> of 486 mJ is based on starting T<sub>J</sub> = 25°C; L = 3 mH, I<sub>AS</sub> = 18 A, V<sub>DD</sub> = 80 V, V<sub>GS</sub> = 10 V. 100% tested at L = 0.1 mH, I<sub>AS</sub> = 51 A.
  Pulsed I<sub>D</sub> please refer to Fig. 11 SOA graph for more details.
  Control problems of the problems of t electro-mechanical application board design.

# TYPICAL CHARACTERISTICS (T<sub>J</sub> = 25°C unless otherwise noted)

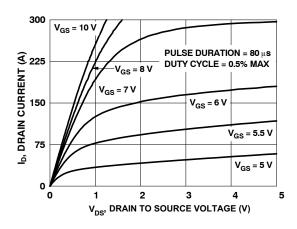


Figure 1. On Region Characteristics

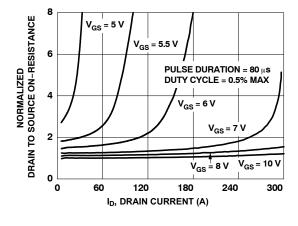


Figure 2. Normalized On-Resistance vs. Drain Current and Gate Voltage

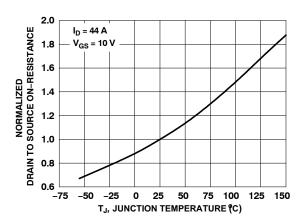


Figure 3. Normalized On Resistance vs. Junction Temperature

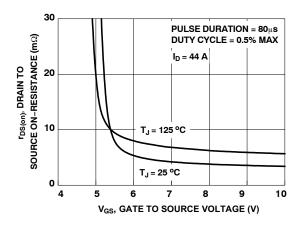


Figure 4. On-Resistance vs. Gate to Source Voltage

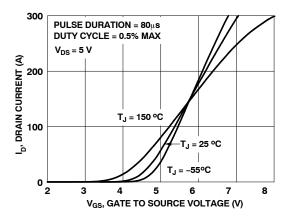


Figure 5. Transfer Characteristics

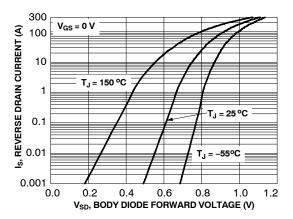


Figure 6. Source to Drain Diode Forward Voltage vs. Source Current

### TYPICAL CHARACTERISTICS (continued)

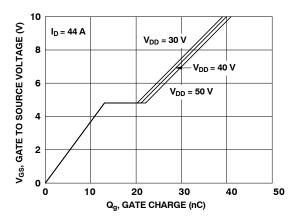


Figure 7. Gate Charge Characteristics

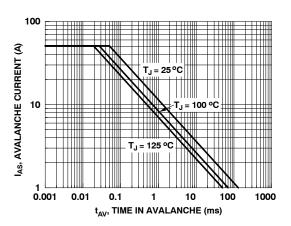


Figure 9. Unclamped Inductive Switching Capability

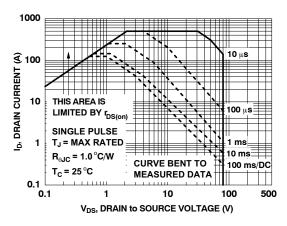


Figure 11. Forward Bias Safe Operating Area

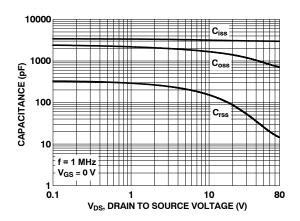


Figure 8. Capacitance vs. Drain to Source Voltage

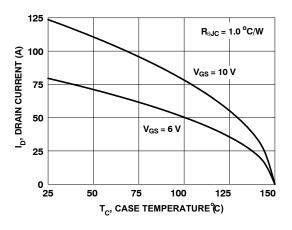


Figure 10. Maximum Continuous Drain Current vs. Case Temperature

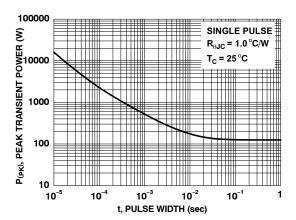


Figure 12. Single Pulse Maximum Power Dissipation

# TYPICAL CHARACTERISTICS (continued)

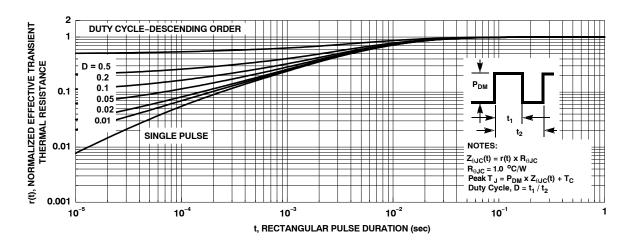


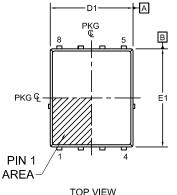
Figure 13. Junction-to-Case Transient Thermal Response Curve

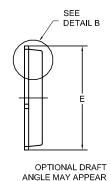
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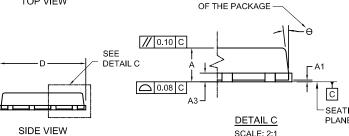


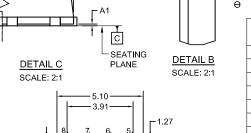


ON FOUR SIDES

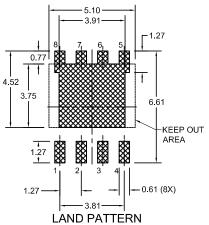
#### NOTES:

- 1. DIMENSIONING AND TOLERANCING PER ASME Y14.5M, 2009.
- 2. CONTROLLING DIMENSION: MILLIMETERS
- 3. COPLANARITY APPLIES TO THE EXPOSED PADS AS WELL AS THE TERMINALS.
- 4. DIMENSIONS D1 AND E1 DO NOT INCLUDE MOLD FLASH, PROTRUSIONS, OR GATE BURRS.
- 5. SEATING PLANE IS DEFINED BY THE TERMINALS. "A1" IS DEFINED AS THE DISTANCE FROM THE SEATING PLANE TO THE LOWEST POINT ON THE PACKAGE BODY.
- 6. IT IS RECOMMENDED TO HAVE NO TRACES OR VIAS WITHIN THE KEEP OUT AREA.





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# RECOMMENDATION

\*FOR ADDITIONAL INFORMATION ON OUR PB-FREE STRATEGY AND SOLDERING DETAILS, PLEASE DOWNLOAD THE ON SEMICONDUCTOR SOLDERING AND MOUNTING TECHNIQUES REFERENCE MANUAL, SOLDERRM/D.

DIM	MILLIMETERS				
Diwi	MIN.	NOM.	MAX.		
Α	0.90	1.00	1.10		
A1	0.00	-	0.05		
b	0.21	0.31	0.41		
b1	0.31	0.41	0.51		
A3	0.15	0.25	0.35		
D	4.90	5.00	5.20		
D1	4.80	4.90	5.00		
D2	3.61	3.82	3.96		
Е	5.90	6.15	6.25		
E1	5.70	5.80	5.90		
E2	3.38	3.48	3.78		
E3	0.30 REF				
E4	0.52 REF				
е	1.27 BSC				
e/2	0.635 BSC				
e1	3.81 BSC				
e2	0.50 REF				
L	0.51	0.66	0.76		
L2	0.05	0.18	0.30		
L4	0.34	0.44	0.54		
Z	0.34 REF				
θ	0°	-	12°		

MILLIMETEDS

(E3) (2X) L4 (4X) b (8X)	
BOTTOM VIEW	

e1

(z) (4X)

┌<sup>(e2)</sup>

-b1 (4X)

**⊕** 0.10**M** C A B

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